TO-220AB

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Top View



AOT20S60-VB Datasheet

N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMA	RY	
V _{DS} (V) at T _J max.	650)
R _{DS(on)} (Ω) at 25 °C	$V_{GS} = 10 V$	0.19
Q _g max. (nC)	106	3
Q _{gs} (nC)	14	
Q _{gd} (nC)	33	
Configuration	Sing	le

GC

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N-Channel MOSFET

FEATURES

- Reduced t_{rr}, Q_{rr}, and I_{RRM}
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q_{rr}
- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Telecommunications
 - Server and telecom power supplies
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Consumer and computing
 - ATX power supplies
- Industrial
 - Welding
 - Battery chargers
- Renewable energy
 - Solar (PV inverters)
- Switch mode power supplies (SMPS)

ABSOLUTE MAXIMUM RATINGS (T _C	= 25 °C, unle	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	650	V
Gate-Source Voltage			V _{GS}	± 30	v
Continuous Drain Current (T ₁ = 150 °C)	V at 10 V	T _C = 25 °C T _C = 100 °C	1	20	
Continuous Drain Current $(1) = 150$ C)	V _{GS} at 10 V	T _C = 100 °C	۱ _D	13	А
Pulsed Drain Current ^a			I _{DM}	60	
Linear Derating Factor				1.7	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	367	mJ
Maximum Power Dissipation			PD	208	W
Operating Junction and Storage Temperature Range	е		T _J , T _{stg}	-55 to +150	°C
Drain-Source Voltage Slope	T _J = 12	25 °C	dV/dt	37	V/ns
Reverse Diode dV/dt ^d			uv/di	31	v/ns
Soldering Recommendations (Peak Temperature) ^c	for 1	0 s		300	°C

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. $V_{DD} = 50$ V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 5.1 A.

c. 1.6 mm from case.

d. $I_{SD} \leq I_D$, dl/dt = 100 A/µs, starting T_J = 25 °C.





Static Vas Vas Vas Vas Vas Vas State Drain-Source Breakdown Voltage V_{DS} Temperature Coefficient $\Delta V_{DS}/T_J$ Reference to 25 °C, Ip = 1 mA - 0.67 - V/2 Gate-Source Threshold Voltage (N) V_{OS} $V_{OS} = V_{OS}$ - 2 - 4 V/2 Gate-Source Threshold Voltage (N) V_{OS} = 2.0 µA 2 - 4 V/2 Gate-Source Threshold Voltage (N) V_{OS} = 2.0 µA - - ± 1.00 nA Gate-Source Chreate Resistance $R_{OS(cn)}$ $V_{DS} = 520 V$, $V_{OS} = 0 V$ - - ± 1 µA Zero Gate Voltage Drain Current I_{DSS} $V_{DS} = 520 V$, $V_{OS} = 0 V$, $V_{OS} = 30 V$, $I_D = 11A$ - 0.19 - Ω Dynamic Dynamic - 7.0 - S Dynamic - 105 - - 105 - - 105 - - 105 - 105 - 105	THERMAL RESISTANCE RATI	NGS							
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TYP. MAX.		UNI		UNIT		
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Ambient	R _{thJA}	- 62						
$\begin{array}{ c c c c c c } \hline PARAMETER & SYMBOL & TEST CONDITIONS & MIN. & TYP. & MAX. & UNI \\ \hline Static & & & & & & & & & & & & & & & & & & &$	Maximum Junction-to-Case (Drain)	R _{thJC}	- 0.5				°C/W		
$\begin{array}{ c c c c c c } \hline PARAMETER & SYMBOL & TEST CONDITIONS & MIN. & TYP. & MAX. & UNI \\ \hline Static & & & & & & & & & & & & & & & & & & &$									
Static Vas Vas Vas Vas Vas Vas State Drain-Source Breakdown Voltage V_{DS} Temperature Coefficient $\Delta V_{DS}/T_J$ Reference to 25 °C, Ip = 1 mA - 0.67 - V/2 Gate-Source Threshold Voltage (N) V_{OS} $V_{OS} = V_{OS}$ - 2 - 4 V/2 Gate-Source Threshold Voltage (N) V_{OS} = 2.0 µA 2 - 4 V/2 Gate-Source Threshold Voltage (N) V_{OS} = 2.0 µA - - ± 1.00 nA Gate-Source Chreate Resistance $R_{OS(cn)}$ $V_{DS} = 520 V$, $V_{OS} = 0 V$ - - ± 1 µA Zero Gate Voltage Drain Current I_{DSS} $V_{DS} = 520 V$, $V_{OS} = 0 V$, $V_{OS} = 30 V$, $I_D = 11A$ - 0.19 - Ω Dynamic Dynamic - 7.0 - S Dynamic - 105 - - 105 - - 105 - - 105 - 105 - 105	SPECIFICATIONS ($T_J = 25 \text{ °C}$, u	Inless otherwi	se noted)						
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static	•	•						•
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D =	250 µA	650	-	-	V
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	, I _D = 1 mA	-	0.67	-	V/°C
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D =	250 µA	2	-	4	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Cata Sauraa Laakaga	1		$V_{GS} = \pm 20$	V	-	-	± 100	nA
$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Gale-Source Leakage	IGSS		$V_{GS} = \pm 30$) V	-	-	± 1	μA
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Zaro Cata Valtaga Drain Current	1	V _{DS} =	= 520 V, V _C	_{GS} = 0 V	-	-	1	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate Voltage Drain Current	DSS	V _{DS} = 520 \			-	-	500	μΑ
DynamicInput Capacitance C_{188} $V_{GS} = 0.V$, $V_{DS} = 100.V$, $f = 1.MHz$ $ 2322$ $ -$ Output Capacitance C_{088} $V_{GS} = 100.V$, $f = 1.MHz$ $ 105$ $ -$ Effective Output Capacitance, Energy Related a $C_{0(er)}$ $V_{DS} = 0.V$ to $520.V$, $V_{GS} = 0.V$ $ 84$ $ -$ Effective Output Capacitance, Time Related b $C_{0(er)}$ $V_{DS} = 0.V$ to $520.V$, $V_{GS} = 0.V$ $ 84$ $ -$ Effective Output Capacitance, Time Related b $C_{0(er)}$ $V_{DS} = 0.V$ to $520.V$, $V_{GS} = 0.V$ $ 84$ $ -$ Intal Gate Charge Gate-Drain Charge Q_{gg} $V_{GS} = 10.V$ $I_D = 11.A, V_{DS} = 520.V$ $ 14$ $ -$ Turn-On Delay Time $t_{d(on)}$ $V_{DD} = 520.V, I_D = 11.A, V_{DS} = 520.V$ $ 68.1002$ $-$ Fall Time t_r $V_{GS} = 10.V, R_g = 9.1.\Omega$ $ 42.84$ $-$ Gate-Drain Charge R_g $f = 1.MHz$, open drain $ 0.78$ $ \Omega$ Fall Time t_r T_r R_g $f = 1.MHz$, open drain $ 0.78$ Ω Drain-Source Body Diode Characteristics V_{SD} $T_J = 25.°C, I_S = 11.A, V_{GS} = 0.V$ $ 0.9.9$ $1.2.V$ Pulsed Diode Forward Current I_{SM} $T_J = 25.°C, I_S = 11.A, V_{GS} = 0.V$ $ 0.9.9$ $1.2.V$ Reverse Recovery Time t_r T_r $T_J = 25.°C, I_S = 11.A, V_{GS} = 0.V$ $-$ <td>Drain-Source On-State Resistance</td> <td>R_{DS(on)}</td> <td>$V_{GS} = 10 V$</td> <td>I</td> <td>l_D = 11 A</td> <td>-</td> <td>0.19</td> <td>-</td> <td>Ω</td>	Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I	l _D = 11 A	-	0.19	-	Ω
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance	9 _{fs}			-	7.0	-	S	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic						-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Input Capacitance	C _{iss}		$V_{CS} = 0$	Ι.	-	2322	-	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C _{oss}	V _{DS} = 100 V,		-	105	-	pF	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance	C _{rss}			-	4	-		
Effective Output Capacitance, Time Related b $C_{o(tr)}$ $ 293$ $ 293$ $-$ Total Gate Charge Q_g Q_g $V_{GS} = 10 \text{ V}$ $I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$ $ 14$ $ nC$ Gate-Drain Charge Q_{gd} Q_{gd} $ 33$ $ 14$ $ nC$ Gate-Drain Charge Q_{gd} Q_{gd} $ 33$ $ 22$ 44 Rise Time $t_{d(on)}$ t_r $V_{DD} = 520 \text{ V}, I_D = 11 \text{ A}, V_{DS} = 520 \text{ V}$ $ 34$ 68 $-$ Turn-On Delay Time $t_{d(off)}$ $V_{CS} = 10 \text{ V}, R_g = 9.1 \Omega$ $ 68$ 102 $ 42$ 84 Fall Time t_f $ 42$ 84 $ 42$ 84 $ 21$ $ 21$ $ 21$ $ 21$ $ 21$ $ 21$ $ 21$ $ 21$ $ 21$ $ -$		C _{o(er)}	$V_{DS} = 0$ V to 520 V, $V_{GS} = 0$ V		-	84	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		C _{o(tr)}			-	293	-		
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge	Qg				-	71	106	
$ \frac{\text{Turn-On Delay Time}}{\text{Rise Time}} & \frac{t_{d(on)}}{t_r} \\ \hline \text{Rise Time} & \frac{t_r}{t_r} \\ \hline \text{Turn-Off Delay Time} & \frac{t_{d(off)}}{t_{d(off)}} \\ \hline \text{Fall Time} & t_f \\ \hline \text{Gate Input Resistance} & R_g & f = 1 \text{ MHz, open drain} & - & 0.78 & - & \Omega \\ \hline \text{Drain-Source Body Diode Characteristics} \\ \hline \text{Continuous Source-Drain Diode Current} & I_S \\ \hline \text{Pulsed Diode Forward Current} & I_{SM} \\ \hline \text{Diode Forward Voltage} & V_{SD} \\ \hline \text{Diode Forward Voltage} & V_{SD} \\ \hline \text{Reverse Recovery Time} & \frac{t_{rr}}{t_r} \\ \hline \text{Pulsed Diode Charace} & O_Q \\ \hline \text{Reverse Recovery Time} \\ \hline Reverse R$	Gate-Source Charge	Q _{gs}	V _{GS} = 10 V I _D = 11 A, V _{DS}		A, $V_{DS} = 520 V$	-	14	-	nC
$ \frac{\text{Turn-On Delay Time}}{\text{Rise Time}} & \frac{t_{d(on)}}{t_r} \\ \hline \text{Rise Time} & \frac{t_r}{t_r} \\ \hline \text{Turn-Off Delay Time} & \frac{t_{d(off)}}{t_{d(off)}} \\ \hline \text{Fall Time} & t_f \\ \hline \text{Gate Input Resistance} & R_g & f = 1 \text{ MHz, open drain} & - & 0.78 & - & \Omega \\ \hline \text{Drain-Source Body Diode Characteristics} \\ \hline \text{Continuous Source-Drain Diode Current} & I_S \\ \hline \text{Pulsed Diode Forward Current} & I_{SM} \\ \hline \text{Diode Forward Voltage} & V_{SD} \\ \hline \text{Diode Forward Voltage} & V_{SD} \\ \hline \text{Reverse Recovery Time} & \frac{t_{rr}}{t_r} \\ \hline \text{Pulsed Diode Charace} & O_Q \\ \hline \text{Reverse Recovery Time} \\ \hline Reverse R$	Gate-Drain Charge					-	33	-	1
Turn-Off Delay Time $t_{d(off)}$ $r_{V_{GS}} = 10 \text{ V}, \text{ R}_g = 9.1 \Omega$ $ 68$ 102 Fall Time t_f $ 42$ 84 Gate Input Resistance R_g $f = 1 \text{ MHz}$, open drain $ 0.78$ $ \Omega$ Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode Current I_S MOSFET symbol showing the integral reverse $p - n$ junction diode $ 21$ A Diode Forward Current I_{SM} $T_J = 25 ^\circ C, I_S = 11 A, V_{GS} = 0 V$ $ 0.9$ 1.2 V Reverse Recovery Time t_{rr} $T_J = 25 ^\circ C, I_F = I_S = 11 A,$ $ 1.0$ 1.2 V	Turn-On Delay Time					-	22	44	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time	t _r				-	34	68	ns
Gate Input Resistance R_g $f = 1 \text{ MHz}$, open drain-0.78- Ω Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode53ADiode Forward VoltageV_SDT_J = 25 °C, I_S = 11 A, V_GS = 0 V-0.91.2VReverse Recovery TimetrrT_J = 25 °C, I_F = I_S = 11 A,-160-ns	Turn-Off Delay Time	t _{d(off)}	V _{GS} =			-	68	102	
Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsMIsMTJ = 25 °C, Is = 11 A, VGS = 0 V-0.91.2VDiode Forward VoltageVsDTJ = 25 °C, Is = 11 A,-160-nsPulsed Diode Forward VoltagetrrTJ = 25 °C, Is = 11 A,-1.2V	Fall Time	t _f			-	42	84		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate Input Resistance	R _g	f = 1 MHz, open drain		-	0.78	-	Ω	
Continuous Source-Drain Diode CurrentIsshowing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsIs $p - n$ junction diode5353Diode Forward VoltageVsDTJ = 25 °C, Is = 11 A, VgS = 0 V-0.91.2VReverse Recovery TimetrrTJ = 25 °C, Is = 11 A,-160-ns	Drain-Source Body Diode Characteristi	cs							
Pulsed Diode Forward CurrentIsmIntegral reverse p - n junction diode53Diode Forward Voltage V_{SD} $T_J = 25 ^{\circ}C$, $I_S = 11 A$, $V_{GS} = 0 V$ -0.91.2 V Reverse Recovery Time t_{rr} $T_J = 25 ^{\circ}C$, $I_F = I_S = 11 A$,-160-ns	Continuous Source-Drain Diode Current	I _S	showing the integral reverse		-	-	21		
Reverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C, I_F = I_S = 11 \ A,$ -160-ns	Pulsed Diode Forward Current	I _{SM}			-	-	53	~	
Reverse Recovery Time t_{rr} $T_J = 25 \ ^{\circ}C, I_F = I_S = 11 \ A,$ -160-ns	Diode Forward Voltage	V _{SD}	T _J = 25 °C	C, I _S = 11 /	A, V _{GS} = 0 V	-	0.9	1.2	V
Payora Pagayan, Chargo $T_J = 25 \text{ °C}, I_F = I_S = 11 \text{ A}, 1.2 \text{ Just}$	-					-	160	-	ns
	-	Q _{rr}	$T_J = 25 \text{ °C}, I_F = I_S = 11 \text{ A},$		-		-	μC	
Beverse Recovery Current I I A				dl/dt = 100 A/µs, V _R = 25 V		-	14	-	

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

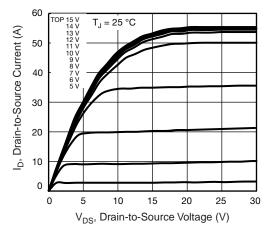


Fig. 1 - Typical Output Characteristics

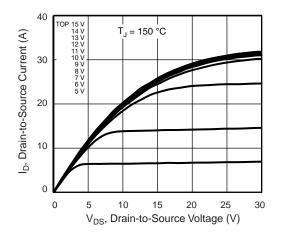


Fig. 2 - Typical Output Characteristics

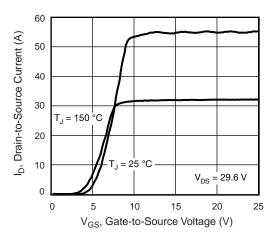


Fig. 3 - Typical Transfer Characteristics

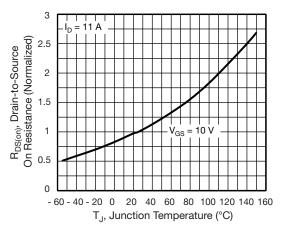


Fig. 4 - Normalized On-Resistance vs. Temperature

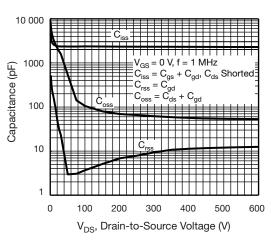


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

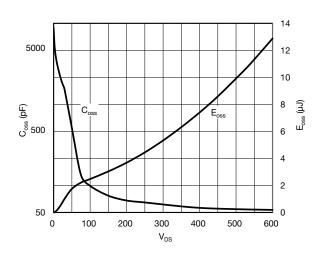


Fig. 6 - C_{oss} and E_{oss} vs. V_{DS}



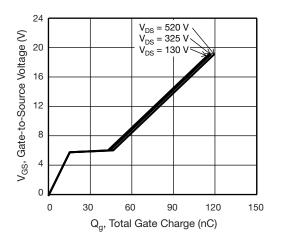


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

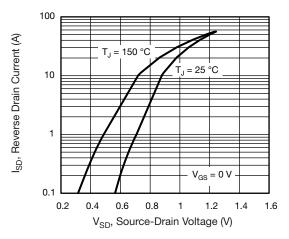


Fig. 8 - Typical Source-Drain Diode Forward Voltage

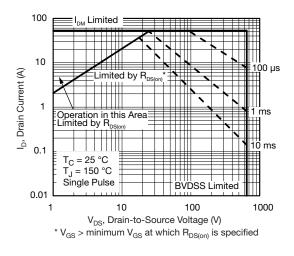


Fig. 9 - Maximum Safe Operating Area

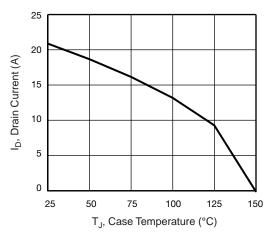


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage





Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms

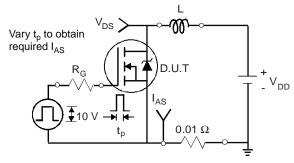


Fig. 15 - Unclamped Inductive Test Circuit

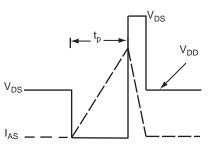


Fig. 16 - Unclamped Inductive Waveforms

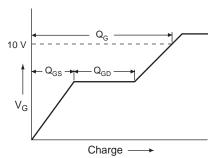
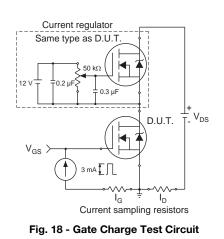
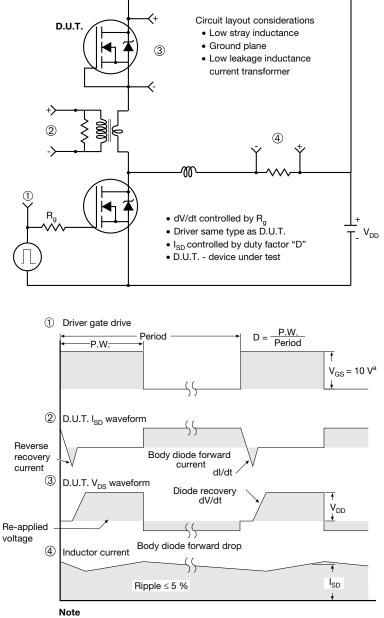


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit

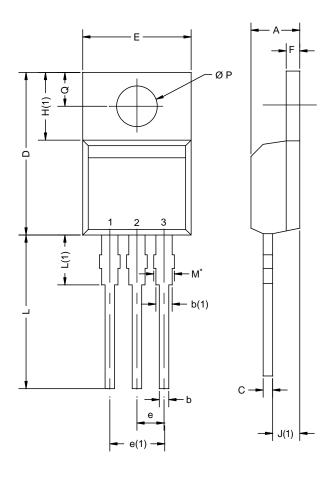


a. $V_{GS} = 5 V$ for logic level devices

Fig. 19 - For N-Channel



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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